

# iMiD 2024

The 24th International Meeting on Information Display  
August 20-23, 2024 / ICC Jeju, Jeju, Korea

<b>Session Title:</b>	<b>09. High Resolution Metrology Inspection and AI Technologies</b>
<b>Session Date:</b>	<b>August 21 (Wed.), 2024</b>
<b>Session Time:</b>	<b>10:50-12:20</b>
<b>Session Room:</b>	<b>Room A (Halla A)</b>

[A09-1] [Invited] 10:50-11:15

## Super-Depth Imaging with Volumetric Reflection Matrix

Ye-Ryoung Lee (Inst. for Basic Science & Korea Univ. & Konkuk Univ., Korea), Dong-Young Kim, Yonghyeon Jo (Inst. for Basic Science & Korea Univ., Korea), Moonseok Kim (Catholic Univ., Korea), and Wonshik Choi (Inst. for Basic Science & Korea Univ., Korea)

[A09-2] [Invited] 11:15-11:40

## Avoiding Frequent Model Retraining for Deep Learning Inspection

Juhyun Ahn, Hwehee Jung, Stephen Lee, and Hyunjun Kim (Cognex, Korea)

[A09-3] [Invited] 11:40-12:05

## Real Performance and Accuracy of XYZ Imaging Systems

Ruud Bouten (Admesy B.V., The Netherlands) and Sungyun Kang (Admesy Technologies Asia, Korea)

[A09-4] 12:05-12:20

## Evaluating HDR Video Quality with Local Gray Fidelity Analysis

Sianyi Huang and Jongseo Lee (Google LLC, USA)